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To be presented by Melanie Berg at the ReSpace/MAPLD 2010 Conference [Military and Aerospace Programmable Logic Devices (MAPLD)], November 1-4, 2010 in Albuquerque, NM, and on http://radhome.gsfc.nasa.gov and http://nepp.nasa.gov/.



Source of Faults: SEEs and Ionizing NASA Particles

Energy emitted from

an atom or nucleus in the form of

waves or particles

· Single Event Effects (SEEs)

- Terrestrial devices are susceptible to faults mostly due to:
 - alpha particles: from packaging and doping and
 - Neutrons: caused by Galactic Cosmic Ray (GCR) Interactions that enter into the earth's atmosphere.
- Devices expected to operate at higher altitude (Aerospace and Military) are more prone to upsets caused by:
 - Heavy ions: direct ionization

MAPLO Albuquergue New Mex

· Protons: secondary effects

presented by Melania Para at the PoSpace/MARLD 2010 Conferen

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Single Event Faults and Common Terminology

 Single Event Latch Up (SEL): Device latches in high current state

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- Single Event Burnout (SEB): Device draws high current and burns out
- Single Event Gate Rupture: (SEGR): Gate destroyed typically in power MOSFETs
- Single Event Transient (SET): current spike due to ionization. Dissipates through bulk
- Single Event Upset (SEU): transient is caught by a memory element
- Single Event Functional Interrupt (SEFI) upset disrupts function

Single Event Effects (SEEs) and IC System Error

- SEUs or SETs can occur in:
 - Combinatorial Logic (including global routes)
 - Sequential Logic
 - Memory Cells
- Depending on the Device and the design, each fault type will:
 - Have a probability of occurrence
 - Either have a significant or insignificant contribution to system error

Every Device has different Error Responses – We must understand the differences and design appropriately

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Example: TMR Mitigation Schemes will use Majority Voting

Majority Voter Best 2 out of 3 Page 24

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Up-to-Date Radiation Effects Knowledge

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 The best designers can create the worst designs:

- Must understand radiation effects in order to mitigate properly
- Each FPGA device has different error modes and signatures
- Mentor has established a close relationship with the radiation effects community
- Knowledge of current FPGA test results is the premise of Precisions mitigation strategies
- Mitigation has been utilized in NASA Goddard Radiation Effects particle accelerator experiments

Voter Insertion

Intelligent handling of many special cases

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- Logic Reduction
- : Primary top-level design outputs
- : Clock Enable Handling
- : Control Domain Crossings
- Multiply-Accumulate Circuits
- : Latches
- : Combinatorial Loops
- : Black Boxes
- We don't have time to discuss all:
 - Primary top-level design outputs
 - : Control Domain Crossings
 - · Black Boxes



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 Most Design guidelines will not allow combinatorial logic after a register directly feeding an output

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- The user has a choice
- Primary top-level design outputs:
 - Mapping register into fabric
 - Tripling top-level IO (or not!!!!!!)
 - Mapping register into pad cell (path convergence)

Common DTMR and GTMR I/O NASA Strategies May not pass Design Path Review IOB IOB Path a a&b or = a&c or 112 112 Path b b&c Path c t a contraction Triple I/O=OFF, OUTFF=FALSE Paged

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